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| Notice of References Cited | Application/Control No. 10/511,457 | Applicant(s)/Patent Under Reexamination NEUMANN, PETER | |
| | Examiner Kiet Doan | Art Unit 2683 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| | A | US-6,370,391 B1 | 04-2002 | Lietsalmi et al. | 455/466 |
| | B | US-6,161,016 A | 12-2000 | Yarwood, Anthony Charles | 455/445 |
| | C | US-6,374,099 B1 | 04-2002 | Bi et al. | 455/404.1 |
| | D | US-5,301,359 A | 04-1994 | Van den Heuvel et al. | 455/524 |
| | E | US-5,335,350 A | 08-1994 | Felderman et al. | 455/17 |
| | F | US-5,630,209 | 05-1997 | Wizgall et al. | 455/521 |
| | G | US-6,115,596 A | 09-2000 | Raith et al. | 455/404.2 |
| | H | US-6,356,767 B2 | 03-2002 | Froula, Donald R. | 455/512 |
| | I | US-6,397,054 B1 | 05-2002 | Hoirup et al. | 455/404.1 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
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| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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